IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Claus Dworski et al. Examiner: Unknown

Serial No.: 10/564,650 Group Art Unit: Unknown

National Stage Filing Date: January 13, 2006 Docket: I431.144.101/FIN 503 PCT/US

Title: ELECTRICAL CIRCUIT AND METHOD FOR TESTING ELECTRONIC COMPONENT

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Supplemental Information Disclosure Statement be entered and the documents listed on attached form 1449 be considered by the Examiner and made of record. Any required copies of patents, publications or other documents are enclosed for the Examiner's review. Pursuant to the provisions of M.P.E.P. 609, Applicant further requests a copy of the 1449 form, marked as being considered and initialled by the Examiner, be returned with the next Official Communication.

Since this Supplemental Information Disclosure Statement is being submitted within three months of filing national application; or date of entry of national application; or before the mailing date of the first Office Action on the merits, a fee has not been enclosed. However, if such fee is required, the Patent Office is hereby authorized to charge Deposit Account No. 500471 for fees as set forth under 37 C.F.R. 1.17(p).

Applicant respectfully requests consideration of these references during prosecution of the above-identified matter. The Examiner is invited to contact the Applicant's representative at the below-listed telephone number if there are any questions regarding this Communication or the tendered references.

Respectfully submitted,

Claus Dworski et al.,

By,

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Dated: February 22, 2006
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Steven E. Dicke
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CERTIFICATE UNDER 37 C.F.R. 1.8: The undersigned hereby certifies that this paper or papers, as described herein, are being deposited in the United States Postal Service, as first class mail, in an envelope address to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on this 22 day of February, 2006.

By Steven E. Dicke
Name: Steven E. Dicke

FORM PTO-1449	Docket No.: I431.144.101/FIN 503 PCT/US	Serial No.: 10/564,650
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	Applicant: Klaus Dworski et al.	
	Filing Date: January 13, 2006	Group Art: Unknown

U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
	AA	2002/0105353	08/2002	Mori et al.			
	AB	3,852,123	12/1974	Goltz			
	AC	4,746,902	05/1988	Tol et al.			
	AD	6,127,869	10/2000	Hirasaka			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Sub Class	Translated Yes No
	AM	0 550 187	07/1993	EPO			Yes
	AN						Yes
	AO						Yes

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AP	A.K. Lu, G.W. Roberts, "An Analog Multi-Tone Signal Generator for Built-In Self-Test Applications", ITC 1994 Proceedings, Baltimore, USA Paper 27.3, pp. 650-659.
	AQ	A.K. Lu, G.W. Roberts, D.A. Johns, "A High-Quality Analog Oscillator Using Oversampling D/A Conversion Techniques", ISCAS 1993 Proceedings, Chicago, May 1993, pp. 1298-1301.
	AR	A.K. Lu, G.W. Roberts, D.A. Johns, "A High-Quality Analog Oscillator Using Oversampling D/A Conversion Techniques", IEEE Trans. On Circuits and Systems - II: Analog and Digital Signal Processing, Vol. 41, No. 7, July 1994.
	AS	M. Hafed, G. Roberts, "Test and Evaluation of Multiple Embedded Mixed-Signal Test Cores", ITC 2002 Proceedings, Baltimore, USA, Paper 35.3, pp. 1022-1030.
	AT	T.A. Rebold, F.H. Irons: "A phase-plane approach to the compensation of high-speed analog-to-digital converters" IEEE International Symposium on Circuits and Systems XP 008036387
	AU	Hofner T.C.: "INL/DNL Measurements for High-Speed ADCS" XP000947286

EXAMINER:	DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.